Revised version

Development of Nano-Device Probing System under Multi-Extreme Conditions

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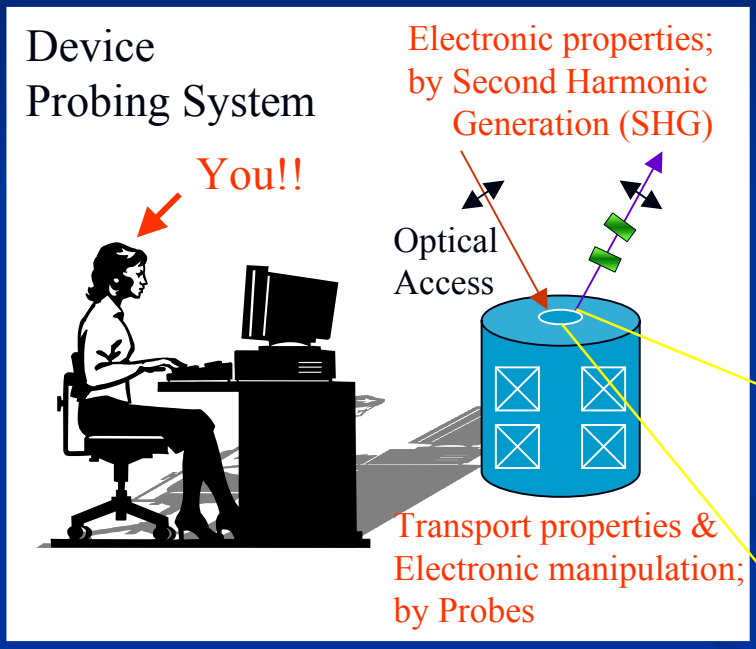

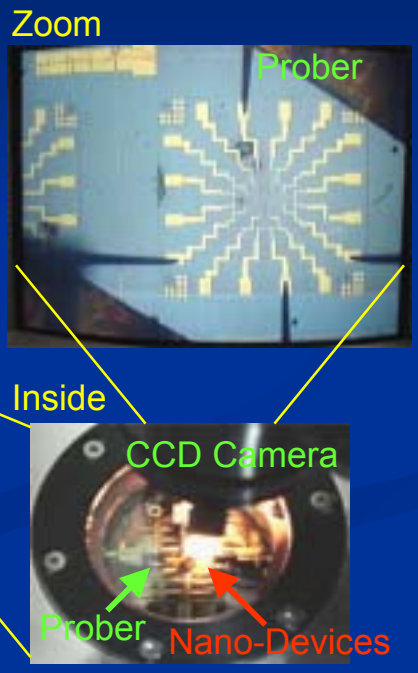

Goal : We will realize a probing system, enabling us to evaluate variable electronic & optical properties of Nano-materials & device, under multi-extreme conditions, Temperature 1.5 ~ 300 K and Magnetic field ~ 30000 Oe.
You can investigate various materials and devices, such as Single-electron, Spintronics, Molecular-electronics devices.
Novel nano-scale measurement technique, such as Electric-field modified SHG, will be also developed.

Challenges : How to apply the magnetic field to the device? although the device is settled in the upper part of the cryostat. Patent pending.

Marketing : We will finish the development of the system within 2 years.
In the last year of this project, our efforts will be focused on the performance-evaluation to commercialize the system, and the marketing.